Docket No. 249705US2SDIV

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

GAU:

IN RE APPLICATION OF: Hideo ANDO, et al.

SERIAL NO: New DIV Application

II 'd DVAMOU

FILED: Herewith EXAMINER:

INFORMATION STORAGE SYSTEM CAPABLE OF RECORDING AND PLAYING BACK A PLURALITY OF STILL PICTURES

# **INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR

FOR:

Applicant(s) wish to disclose the following information.

#### REFERENCES

The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed
references were provided in previous U.S. Application Nos. 09/348,267, filed July 7, 1999, 09/630,430, filed
August 1, 2000, and 10/076,284, filed February 19, 2002.

☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

# RELATED CASES

Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present
application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s)
is attached along with PTO 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

# DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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22850

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Scott A. McKeown

Registration No. 42,866

Name	Form PTO 1449			ATTY DOCKET NO.		SERIAL NO.			
Hideo ANDO, et al.	(Modified)	(Modified) PATENT AND TRADEMARK OFFICE		249705US2SDIV		New DIV Application			
FILING DATE   GROUP					APPLICANT				
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			APPLICANT					
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INITIAL		NUMBER			CLASS	CLASS	IF A	PPROPRIATE
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